N-channel TrenchMOS logic level FET

11 September 2012

Product data sheet

## 1. Product profile

### 1.1 General description

Logic level N-channel MOSFET in a SOT78 package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

### **1.2 Features and benefits**

- AEC Q101 compliant
- Repetitive avalanche rated
- Suitable for thermally demanding environments due to 175 °C rating
- True logic level gate with VGS(th) rating of greater than 0.5V at 175 °C

### 1.3 Applications

- 12 V Automotive systems
- Motors, lamps and solenoid control
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

### 1.4 Quick reference data

Table 1. Qu	lick reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	60	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 5 V; T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>	[1]	-	-	120	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>		-	-	349	W
Static charac	teristics						
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>		-	2.2	2.8	mΩ
Dynamic cha	racteristics						
Q <sub>GD</sub>	gate-drain charge	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; V <sub>DS</sub> = 48 V; <u>Fig. 13; Fig. 14</u>		-	41.2	-	nC

[1] Continuous current is limited by package.





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## 2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	mb	D
2	D	drain		
3	S	source		G C C C C C C C C C C C C C C C C C C C
mb	D	mounting base; connected to drain		mbb076 S
			TO-220AB (SOT78A)	

## 3. Ordering information

Table 3. Ordering information						
Type number	Package					
	Name	Description	Version			
BUK952R8-60E	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78A			

## 4. Marking

Table 4. Marking codes	
Type number	Marking code
BUK952R8-60E	BUK952R8-60E

## 5. Limiting values

#### Table 5.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Мах	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	60	V
V <sub>DGR</sub>	drain-gate voltage	R <sub>GS</sub> = 20 kΩ		-	60	V
V <sub>GS</sub>	gate-source voltage	$T_j \le 175 \text{ °C}; \text{ Pulsed}$	[1][2]	-15	15	V
		T <sub>j</sub> ≤ 175 °C; DC		-10	10	V
I <sub>D</sub>	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 5 V; <u>Fig. 1</u>	[3]	-	120	А
		T <sub>mb</sub> = 100 °C; V <sub>GS</sub> = 5 V; <u>Fig. 1</u>	[3]	-	120	А

BUK952R8-60E

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Symbol	Parameter	Conditions		Min	Мах	Unit
I <sub>DM</sub>	peak drain current	$T_{mb}$ = 25 °C; pulsed; $t_p \le 10 \ \mu s$ ; Fig. 4		-	952	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>		-	349	W
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-dra	in diode					
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	[3]	-	120	А
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^\circ C$		-	952	А
Avalanche	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\begin{split} & I_{D} = 120 \text{ A};  \text{V}_{\text{sup}} \leq 60  \text{V};  \text{R}_{\text{GS}} = 50  \Omega; \\ & \text{V}_{\text{GS}} = 5  \text{V};  \text{T}_{\text{j(init)}} = 25 ^{\circ}\text{C}; \text{ unclamped}; \\ & \underline{\text{Fig. 3}} \end{split}$	[4][5]	-	655	mJ

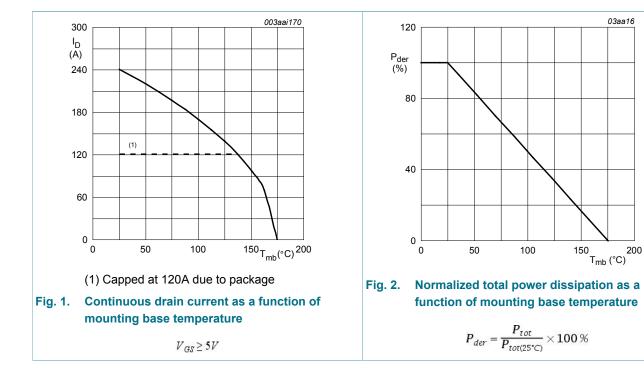
Accumulated pulse duration up to 50 hours delivers zero defect ppm [1]

Significantly longer life times are achieved by lowering  $T_{\rm j}$  and or  $V_{\rm GS}$ [2]

Continuous current is limited by package. [3]

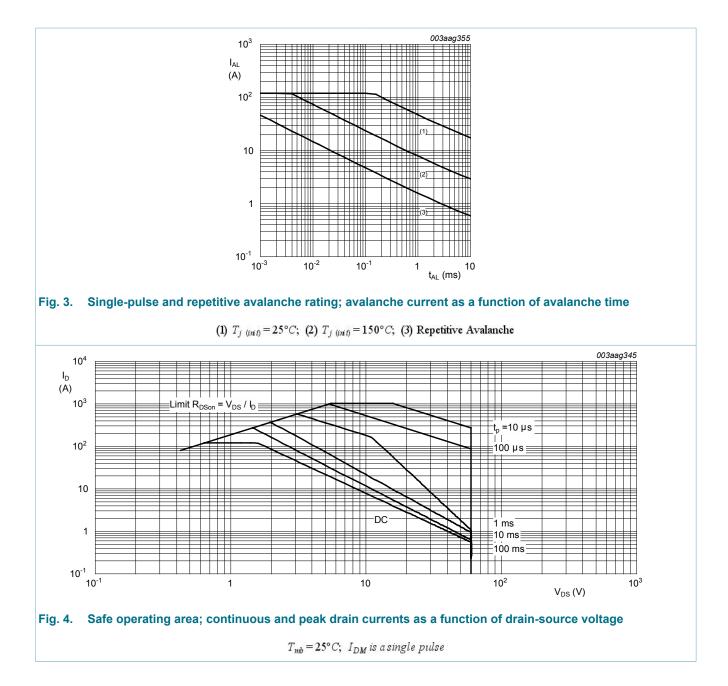
Single-pulse avalanche rating limited by maximum junction temperature of 175 °C. [4] [5]

Refer to application note AN10273 for further information.



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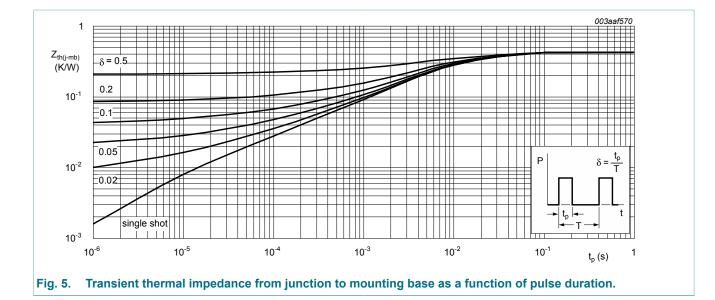


## 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	Fig. 5	-	-	0.43	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	vertical in still air	-	60	-	K/W

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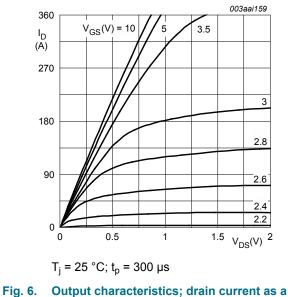


#### **Characteristics** 7.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics	· · ·	I			
V <sub>(BR)DSS</sub>	drain-source	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = 25 °C	60	-	-	V
	$\begin{array}{c} \mbox{drain-source} & \mbox{l}_D = 250 \ \mu \mbox{A} \\ \mbox{l}_D = 1 \ m \mbox{A}; \mbox{A} \\ \mbox{Fig. 9} \\ \mbox{l}_D = 1 \ m \mbox{A}; \mbox{A} \\ \mbox{Fig. 9} \\ \mbox{l}_D = 1 \ m \mbox{A}; \mbox{A} \\ \mbox{Fig. 9} \\ \mbox{l}_D = 1 \ m \mbox{A}; \mbox{A} \\ \mbox{Fig. 9} \\ \mbox{l}_D = 1 \ m \mbox{A}; \mbox{A} \\ \mbox{Fig. 9} \\ \mbox{V}_{DS} = 60 \ \mbox{V}; \\ \mbox{V}_{DS} = 60 \ \mbox{V}; \\ \mbox{V}_{DS} = 60 \ \mbox{V}; \\ \mbox{V}_{QS} = -10 \ \mbox{V}; \\ \mbox{V}_{QS} = -10 \ \mbox{V}; \\ \mbox{V}_{QS} = 5 \ \mbox{V}; \mbox{I} \\ \mbox{V}_{QS} = 5 \ \mbox{V}; \\ \mbox{I} \\ \mbox{I} \\ \mbox{V}_{QS} = 5 \ \mbox{V}; \\ \mbox{I} \\ \mbox{I} \\ \mbox{V}_{QS} = 5 \ \mbox{V}; \\ \mbox{I} \mbox{I} \\ \mbox{I} \\ \mbox{I} \mbox{I} \\ \mbox{I} \mbox{I} \mbox{I} \mbox{I} \mbox{I} \\ \mbox{I} \mbox{I}$	I <sub>D</sub> = 250 μA; V <sub>GS</sub> = 0 V; T <sub>j</sub> = -55 °C	54	-	-	V
V <sub>GS(th)</sub>	•	$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = 25 °C; Fig. 9; Fig. 10	1.4	1.7	2.1	V
		$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = -55 °C; Fig. 9	-	-	2.45	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ Fig. 9	0.5	-	-	V
I <sub>DSS</sub>	DSS drain leakage current	$V_{DS}$ = 60 V; $V_{GS}$ = 0 V; $T_j$ = 25 °C	-	0.08	1	μA
		V <sub>DS</sub> = 60 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 175 °C	-	-	500	μA
I <sub>GSS</sub> gate I	gate leakage current	$V_{GS}$ = 10 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	2	100	nA
		$V_{GS}$ = -10 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	2	100	nA
R <sub>DSon</sub>		V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>	-	2.2	2.8	mΩ
	resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; Fig. 11	-	2	2.6	mΩ
		V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 175 °C; Fig. 12; Fig. 11	-	-	6.2	mΩ
Dynamic ch	aracteristics	·	1			
Q <sub>G(tot)</sub>	total gate charge	I <sub>D</sub> = 25 A; V <sub>DS</sub> = 48 V; V <sub>GS</sub> = 5 V;	-	120	-	nC
Q <sub>GS</sub>	gate-source charge	Fig. 13; Fig. 14	-	25.6	-	nC

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Q <sub>GD</sub>	gate-drain charge		-	41.2	-	nC
C <sub>iss</sub>	input capacitance	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz;	-	13070	17450	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; <u>Fig. 15</u>	-	1051	1260	pF
C <sub>rss</sub>	reverse transfer capacitance		-	558	770	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 25 V; R <sub>L</sub> = 1.8 Ω; V <sub>GS</sub> = 5 V;	-	71	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 5 \Omega$	-	119	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	224	-	ns
t <sub>f</sub>	fall time		-	128	-	ns
-0	internal drain inductance	from upper edge of drain mounting base to center of die	-	2.5	-	nH
		from drain lead 6mm from package to centre of die	-	4.5	-	nH
L <sub>S</sub>	internal source inductance	from source lead to source bonding pad	-	7.5	-	nH
Source-dra	in diode					
V <sub>SD</sub>	source-drain voltage	I <sub>S</sub> = 25 A; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C; <u>Fig. 16</u>	-	0.77	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_{S}$ = 20 A; dI <sub>S</sub> /dt = -100 A/µs; V <sub>GS</sub> = 0 V;	-	53	-	ns
Q <sub>r</sub>	recovered charge	V <sub>DS</sub> = 25 V	-	98	-	nC





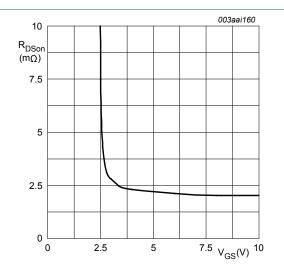
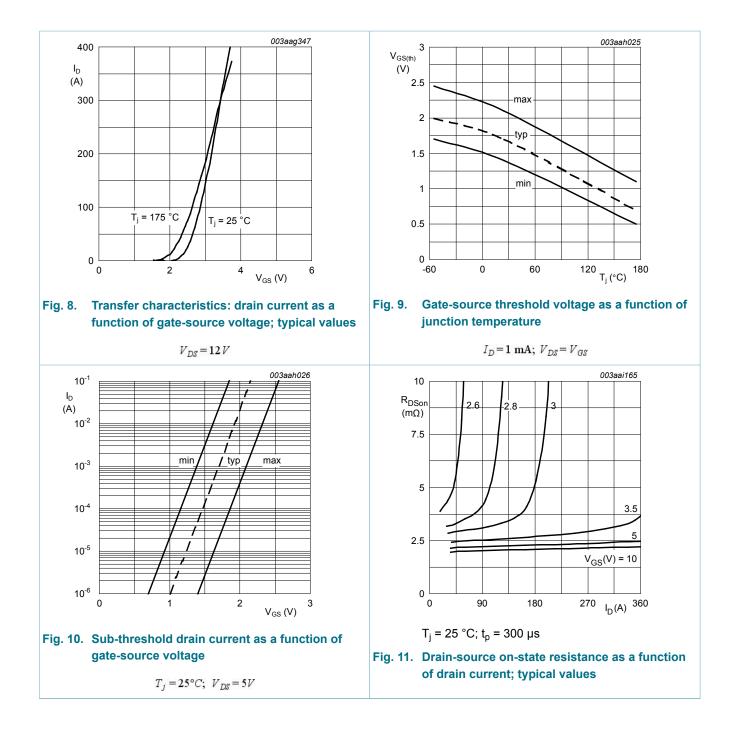


Fig. 7. Drain-source on-state resistance as a function of gate-source voltage; typical values

 $T_j = 25^{\circ}C; \ I_D = 25A$ 

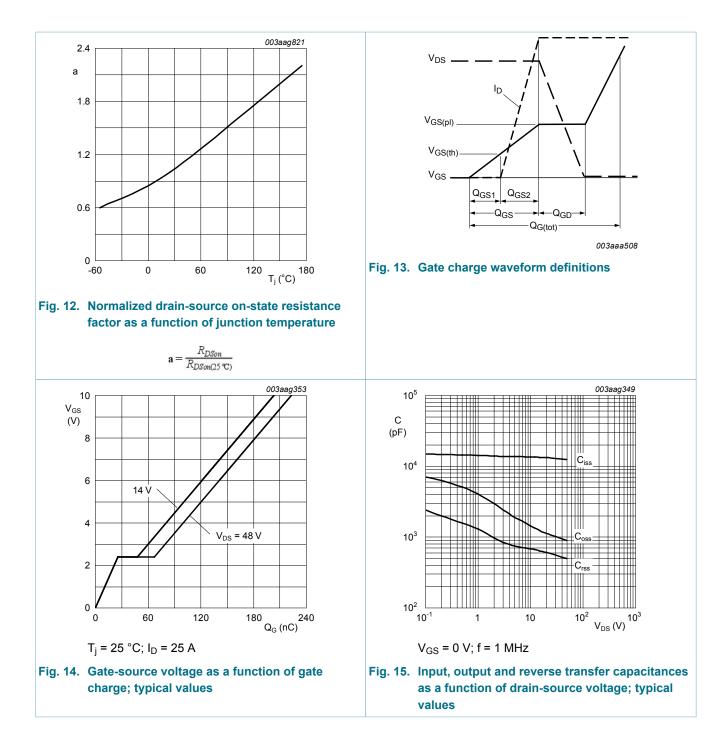
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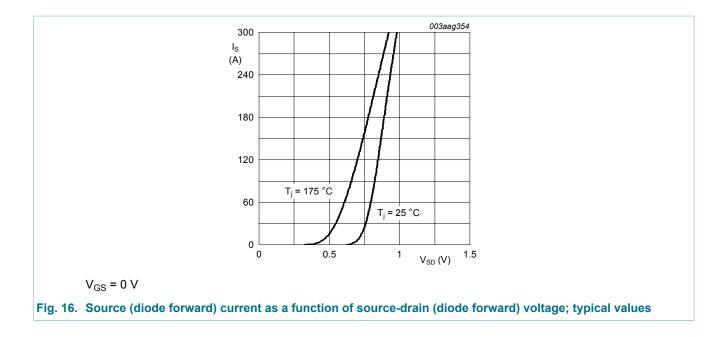
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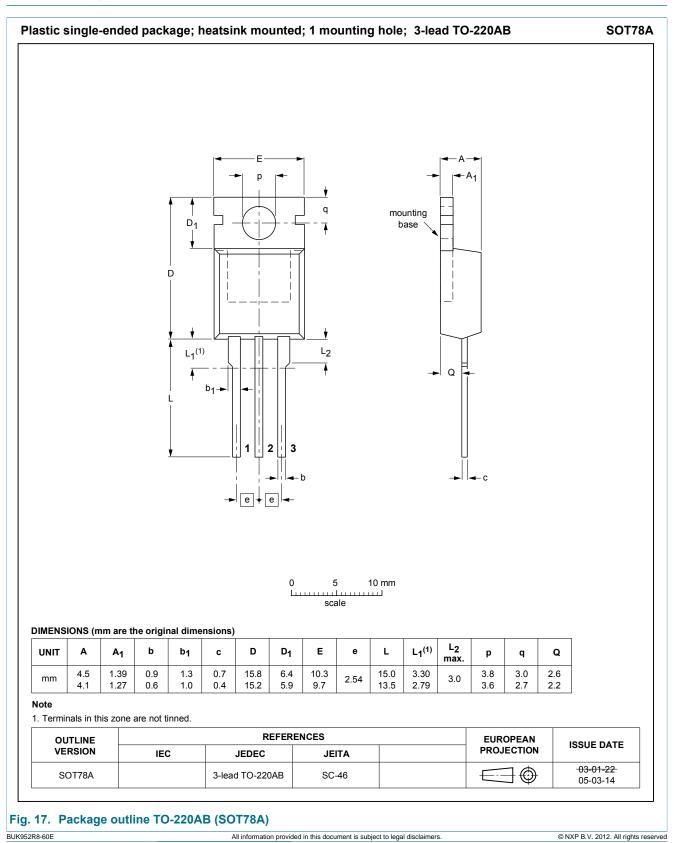
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## 8. Package outline



Product data sheet

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### 9. Legal information

#### 9.1 Data sheet status

Document status [1][2]	Product status [ <u>3]</u>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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